


<b>Search Notes</b> 	<b>Application/Control No.</b> 10537001	<b>Applicant(s)/Patent Under Reexamination</b> AKIYAMA ET AL.
	<b>Examiner</b> Shin, Dana	<b>Art Unit</b> 1635

SEARCHED			
Class	Subclass	Date	Examiner
536	23.1, 24.5	2-9-07	DS
514	44	2-9-07	DS

SEARCH NOTES		
Search Notes	Date	Examiner
EAST -updated, search strategy attached.	2-8-07	DS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner